

UNISONIC TECHNOLOGIES CO., LTD

UT50N04H Preliminary Power MOSFET

50A, 40V N-CHANNEL POWER MOSFET

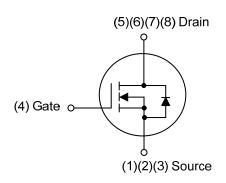
■ DESCRIPTION

The UTC **UT50N04H** is a N-channel enhancement MOSFET using UTC's advanced technology to provide the customers with perfect $R_{DS(ON)}$ and high switching speed.

■ FEATURES

- * $R_{DS(ON)} \le 5.3 \text{ m}\Omega$ @ $V_{GS}=10V$, $I_D=25A$
- * High Switching Speed

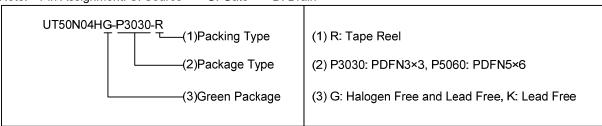
■ SYMBOL

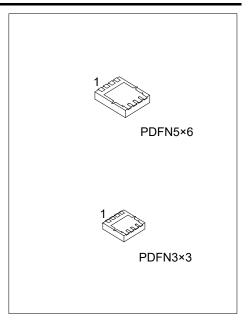




Ordering Number		Daalsana	Pin Assignment							Daakina	
Lead Free	Halogen Free	Package	age 1 2 3 4 5 6		6	7	8	Packing			
UT50N04HL-P3030-R	UT50N04HG-P3030-R	PDFN3×3	S	S	S	G	D	D	D	D	Tape Reel
UT50N04HL-P5060-R	UT50N04HG-P5060-R	PDFN5×6	S	S	S	G	D	D	D	D	Tape Reel

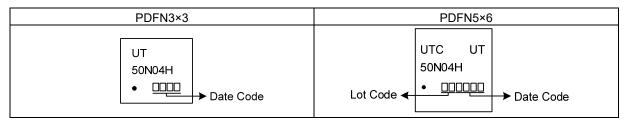
Note: Pin Assignment: S: Source G: Gate D: Drain





www.unisonic.com.tw 1 of 7

■ MARKING



■ ABSOLUTE MAXIMUM RATINGS

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V _{DSS}	40	V	
Gate-Source Voltage	Sate-Source Voltage		±20	V	
Drain Current	Continuous (V _{GS} =10V)	I _D	50	Α	
	Pulsed(Note 2)	I _{DM}	100	Α	
Avalanche Energy	lanche Energy Single Pulsed (Note 3)		84	mJ	
Peak Diode Recovery	dv/dt (Note 4)	dv/dt	dv/dt 1.1		
Power Dissipation	PDFN3×3	P_D	32	W	
	PDFN5×6		41	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55 ~ +175	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 0.1mH, I_{AS} = 41A, V_{DD} = 25V, R_{G} = 25 Ω , Starting T_{J} = 25°C
- 4. IsD \leq 30A, di/dt \leq 200A/ μ s, VDD \leq BVDSS, Starting TJ = 25°C

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT		
IJunction to Ambient	PDFN3×3	0	75 (Note)	°C/W		
	PDFN5×6	θ _{JA}	65 (Note)	°C/W		
Junction to Case	PDFN3×3	0	3.9 (Note)	°C/W		
	PDFN5×6	θις	3.04 (Note)	°C/W		

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

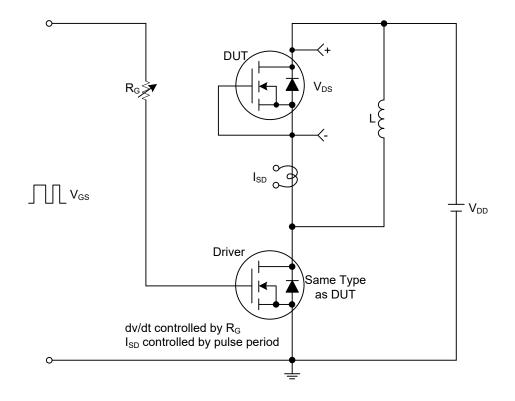
■ **ELECTRICAL CHARACTERISTICS** (T_J=25°C, unless otherwise specified)

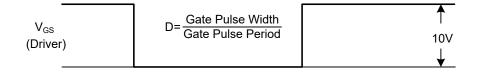
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250µA	40			V			
Drain-Source Leakage Current	I _{DSS}	V _{DS} =40V, V _{GS} =0V			1	μA			
Forward	Igss	V _{GS} =+20V, V _{DS} =0V			+100	nA			
Gate- Source Leakage Current Reverse		V _{GS} =-20V, V _{DS} =0V			-100	nA			
ON CHARACTERISTICS									
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	2.0		4.0	V			
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =25A			5.3	mΩ			
DYNAMIC PARAMETERS									
Input Capacitance	Ciss			2307		pF			
Output Capacitance	Coss	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		268		pF			
Reverse Transfer Capacitance	Crss			211		pF			
SWITCHING PARAMETERS									
Total Gate Charge	Q _G	\/=22\/ \/=10\/ -=50A		62		nC			
Gate to Source Charge	Q _G s	V _{DS} =32V, V _{GS} =10V, I _D =50A (Note 2)		8		nC			
Gate to Drain Charge	Q_{GD}	(Note 2)		34		nC			
Turn-ON Delay Time	t _{D(ON)}			12		ns			
Rise Time	t _R	V _{DD} =20V, V _{GS} =10V, I _D =50A,		15		ns			
Turn-OFF Delay Time	t _{D(OFF)}	R _G =3.3Ω, (Note 2)		42		ns			
Fall-Time	t _F			27		ns			
SOURCE- DRAIN DIODE RATINGS AND CH	IARACTERIS	rics							
Maximum Continuous Drain-Source Diode	Is				50	Α			
Forward Current					50	А			
Maximum Pulsed Drain-Source Diode	I _{SM}				100	Α			
Forward Current	ISM				100	^			
Drain-Source Diode Forward Voltage	VsD	Is=50A,V _{GS} =0V			1.4	V			
Body Diode Reverse Recovery Time	t _{rr}	 I _F =30A,V _{GS} =0V, di/dt=100A/μs		19		ns			
Body Diode Reverse Recovery Charge	Qrr			5		nC			

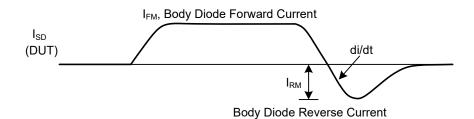
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

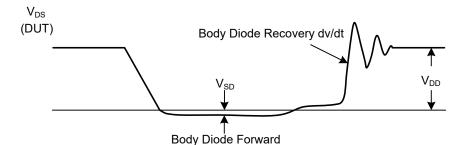
^{2.} Essentially independent of operating ambient temperature.

■ TEST CIRCUITS AND WAVEFORMS



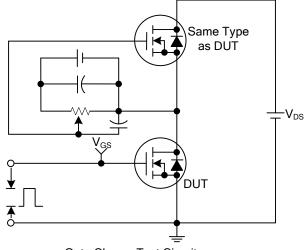


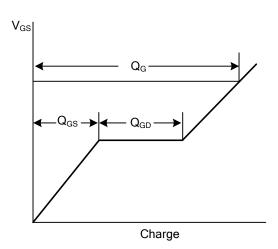




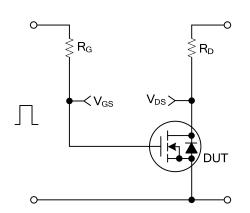
Peak Diode Recovery dv/dt Test Circuit and Waveforms

Voltage Drop

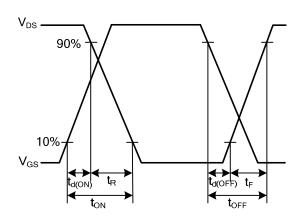




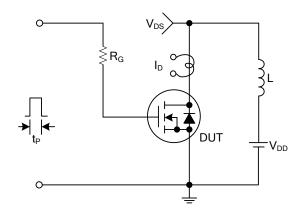
Gate Charge Test Circuit Gate Charge Waveforms



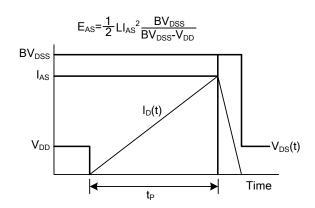
Resistive Switching Test Circuit



Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. UTC reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

